

Materials List for

Active Probe Atomic Force Microscopy with Quattro-Parallel Cantilever Arrays for High-Throughput Large-Scale Sample Inspection

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Materials

Name	Company	Catalog Number	Comments
Active-Cantilever	nano analytik GmbH	AC-10-2012	AFM Probe
E-Beam	EBX-30, INC	012323-15	Mask patterning instrument
Highly Oriented Pyrolytic Graphite – HOPG	TED PELLA, INC	626-10	AFM calibration sample
Mask Sample	Nanda Technologies GmbH	Test substrate	EUV Mask Sample substrate
NANO-COMPAS-PRO	nano analytik GmbH	23-2016	AFM Software
nanoMetronom 20	nano analytik GmbH	1-343-2020	AFM Instrument